Welcome to E-XFL.COM

Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	400MHz
Co-Processors/DSP	Communications; QUICC Engine, Security; SEC
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	740-LBGA
Supplier Device Package	740-TBGA (37.5x37.5)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8360ezuagdga

This figure shows the undershoot and overshoot voltage of the PCI interface of the device for the 3.3-V signals, respectively.

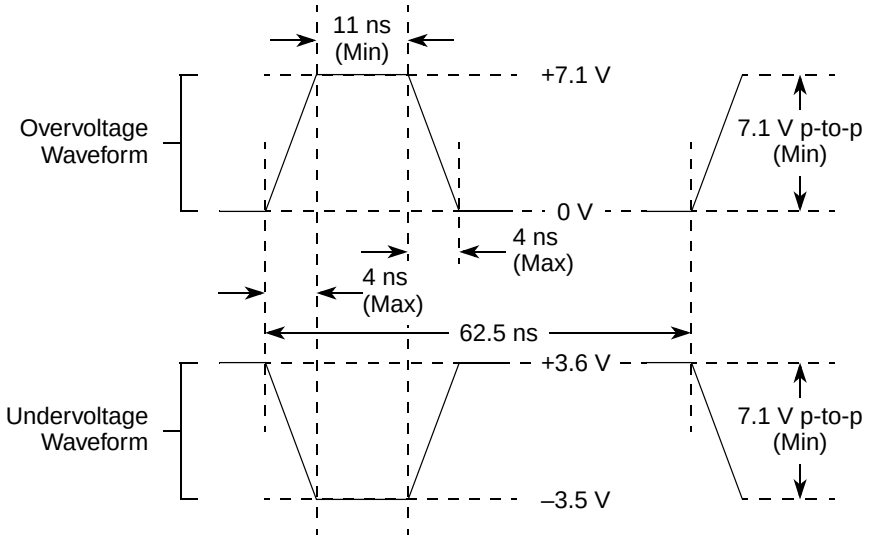


Figure 4. Maximum AC Waveforms on PCI interface for 3.3-V Signaling

2.1.3 Output Driver Characteristics

This table provides information on the characteristics of the output driver strengths. The values are preliminary estimates.

Table 3. Output Drive Capability

Driver Type	Output Impedance (Ω)	Supply Voltage
Local bus interface utilities signals	42	OV_{DD} = 3.3 V
PCI signals	25	
PCI output clocks (including PCI_SYNC_OUT)	42	
DDR signal	20 36 (half-strength mode)[1]	GV_{DD} = 2.5 V
DDR2 signal	18 36 (half-strength mode)[1]	GV_{DD} = 1.8 V
10/100/1000 Ethernet signals	42	LV_{DD} = 2.5/3.3 V
DUART, system control, I^2C, SPI, JTAG	42	OV_{DD} = 3.3 V
GPIO signals	42	OV_{DD} = 3.3 V LV_{DD} = 2.5/3.3 V

Note:
1. DDR output impedance values for half strength mode are verified by design and not tested.

2.2 Power Sequencing

This section details the power sequencing considerations for the MPC8360E/58E.

2.2.1 Power-Up Sequencing

MPC8360E/58E does not require the core supply voltage (V_{DD} and AV_{DD}) and I/O supply voltages (GV_{DD}, LV_{DD}, and OV_{DD}) to be applied in any particular order. During the power ramp up, before the power supplies are stable and if the I/O voltages are supplied before the core voltage, there may be a period of time that all input and output pins are actively be driven and cause contention and excessive current from 3A to 5A. In order to avoid actively driving the I/O pins and to eliminate excessive current draw, apply the core voltage (V_{DD}) before the I/O voltage (GV_{DD}, LV_{DD}, and OV_{DD}) and assert $\overline{\text{PORESET}}$ before the power supplies fully ramp up. In the case where the core voltage is applied first, the core voltage supply must rise to 90% of its nominal value before the I/O supplies reach 0.7 V, see this figure.

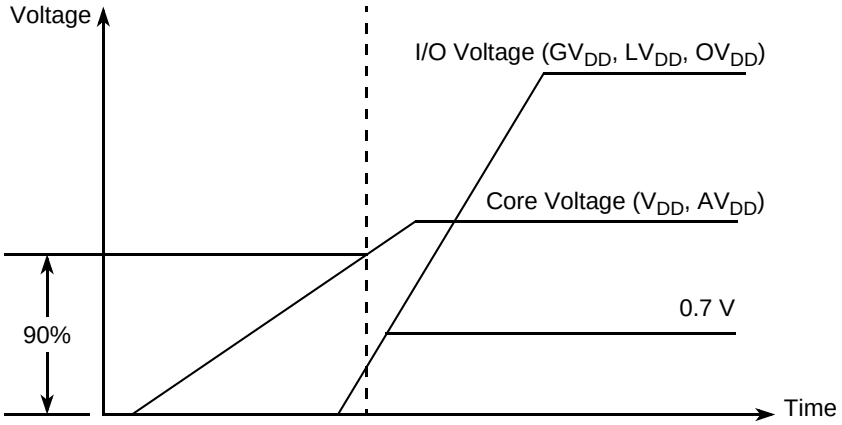


Figure 5. Power Sequencing Example

I/O voltage supplies (GV_{DD}, LV_{DD}, and OV_{DD}) do not have any ordering requirements with respect to one another.

2.2.2 Power-Down Sequencing

The MPC8360E/58E does not require the core supply voltage and I/O supply voltages to be powered down in any particular order.

3 Power Characteristics

The estimated typical power dissipation values are shown in these tables.

Table 4. MPC8360E TBGA Core Power Dissipation[1]

Core Frequency (MHz)	CSB Frequency (MHz)	QUICC Engine Frequency (MHz)	Typical	Maximum	Unit	Notes
266	266	500	5.0	5.6	W	2, 3, 5
400	266	400	4.5	5.0	W	2, 3, 4
533	266	400	4.8	5.3	W	2, 3, 4
667	333	400	5.8	6.3	W	3, 6, 7, 8
500	333	500	5.9	6.4	W	3, 6, 7, 8

5.3 QUICC Engine Block Operating Frequency Limitations

This section specify the limits of the AC electrical characteristics for the operation of the QUICC Engine block's communication interfaces.

NOTE

The settings listed below are required for correct hardware interface operation. Each protocol by itself requires a minimal QUICC Engine block operating frequency setting for meeting the performance target. Because the performance is a complex function of all the QUICC Engine block settings, the user should make use of the QUICC Engine block performance utility tool provided by Freescale to validate their system.

This table lists the maximal QUICC Engine block I/O frequencies and the minimal QUICC Engine block core frequency for each interface.

Table 13. QUICC Engine Block Operating Frequency Limitations

Interface	Interface Operating Frequency (MHz)	Max Interface Bit Rate (Mbps)	Min QUICC Engine Operating Frequency[1] (MHz)	Notes
Ethernet Management: MDC/MDIO	10 (max)	10	20	—
MII	25 (typ)	100	50	—
RMII	50 (typ)	100	50	—
GMII/RGMII/TBI/RTBI	125 (typ)	1000	250	—
SPI (master/slave)	10 (max)	10	20	—
UCC through TDM	50 (max)	70	8 × F	2
MCC	25 (max)	16.67	16 × F	2, 4
UTOPIA L2	50 (max)	800	2 × F	2
POS-PHY L2	50 (max)	800	2 × F	2
HDLC bus	10 (max)	10	20	—
HDLC/transparent	50 (max)	50	8/3 × F	2, 3
UART/async HDLC	3.68 (max internal ref clock)	115 (Kbps)	20	—
BISYNC	2 (max)	2	20	—
USB	48 (ref clock)	12	96	—

Notes:

1. The QUICC Engine module needs to run at a frequency higher than or equal to what is listed in this table.
2. 'F' is the actual interface operating frequency.\
3. The bit rate limit is independent of the data bus width (that is, the same for serial, nibble, or octal interfaces).
4. TDM in high-speed mode for serial data interface.

6 DDR and DDR2 SDRAM

This section describes the DC and AC electrical specifications for the DDR and DDR2 SDRAM interface of the MPC8360E/58E.

Table 21. DDR and DDR2 SDRAM Output AC Timing Specifications for Source Synchronous Mode (continued)

At recommended operating conditions with GV_{DD} of (1.8 V or 2.5 V) ± 5%.

Parameter[8]	Symbol[1]	Min	Max	Unit	Notes
MDQS epilogue end	t_{DDKHME}	–0.6	0.9	ns	7

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
2. All MCK/$\overline{\text{MCK}}$ referenced measurements are made from the crossing of the two signals ±0.1 V.
3. In the source synchronous mode, MCK/$\overline{\text{MCK}}$ can be shifted in ¼ applied cycle increments through the clock control register. For the skew measurements referenced for t_{AOSKEW} it is assumed that the clock adjustment is set to align the address/command valid with the rising edge of MCK.
4. ADDR/CMD includes all DDR SDRAM output signals except MCK/$\overline{\text{MCK}}$, $\overline{\text{MCS}}$, and MDQ/MECC/MDM/MDQS. For the ADDR/CMD setup and hold specifications, it is assumed that the clock control register is set to adjust the memory clocks by ½ applied cycle.
5. Note that t_{DDKHMH} follows the symbol conventions described in note 1. For example, t_{DDKHMH} describes the DDR timing (DD) from the rising edge of the MCK(n) clock (KH) until the MDQS signal is valid (MH). t_{DDKHMH} can be modified through control of the DQSS override bits in the TIMING_CFG_2 register. In source synchronous mode, this is typically set to the same delay as the clock adjust in the CLK_CNTL register. The timing parameters listed in the table assume that these two parameters have been set to the same adjustment value. Refer *MPC8360E PowerQUICC II Pro Integrated Communications Processor Reference Manual* for a description and understanding of the timing modifications enabled by use of these bits.
6. Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the device.
7. All outputs are referenced to the rising edge of MCK(n) at the pins of the device. Note that t_{DDKHMP} follows the symbol conventions described in note 1.
8. AC timing values are based on the DDR data rate, which is twice the DDR memory bus frequency.
9. In rev. 2.0 silicon, t_{DDKHMH} maximum meets the specification of 0.6 ns. In rev. 2.0 silicon, due to errata, t_{DDKHMH} minimum is –0.9 ns. Refer to Errata DDR18 in *Chip Errata for the MPC8360E, Rev. 1*.

This figure shows the DDR SDRAM output timing for address skew with respect to any MCK.

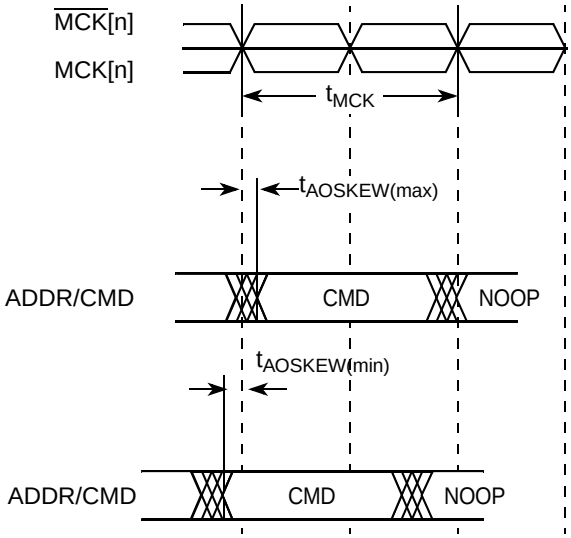


Figure 7. Timing Diagram for t_{AOSKEW} Measurement

8.2.1.2 GMII Receive AC Timing Specifications

This table provides the GMII receive AC timing specifications.

Table 28. GMII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit	Notes
RX_CLK clock period	t_{GRX}	—	8.0	—	ns	—
RX_CLK duty cycle	t_{GRXH}/t_{GRX}	40	—	60	%	—
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{GRDVKH}	2.0	—	—	ns	—
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{GRDXKH}	0.2	—	—	ns	2
RX_CLK clock rise time, (20% to 80%)	t_{GRXR}	—	—	1.0	ns	—
RX_CLK clock fall time, (80% to 20%)	t_{GRXF}	—	—	1.0	ns	—

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. In rev. 2.0 silicon, due to errata, t_{GRDXKH} minimum is 0.5 which is not compliant with the standard. Refer to Errata *QE_ENET18* in *Chip Errata for the MPC8360E, Rev. 1*.

This figure shows the GMII receive AC timing diagram.

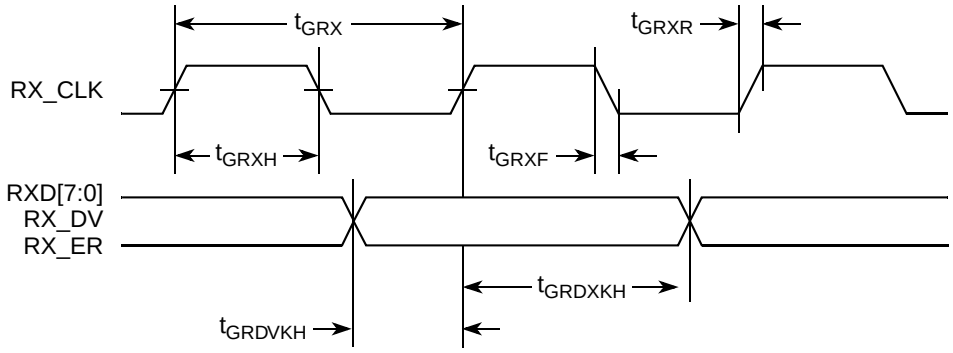


Figure 11. GMII Receive AC Timing Diagram

8.2.2 MII AC Timing Specifications

This section describes the MII transmit and receive AC timing specifications.

8.2.2.1 MII Transmit AC Timing Specifications

This table provides the MII transmit AC timing specifications.

Table 29. MII Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit
TX_CLK clock period 10 Mbps	t_{MTX}	—	400	—	ns
TX_CLK clock period 100 Mbps	t_{MTX}	—	40	—	ns
TX_CLK duty cycle	t_{MTXH}/t_{MTX}	35	—	65	%
TX_CLK to MII data TXD[3:0], TX_ER, TX_EN delay	t_{MTKHDX} t_{MTKHDV}	1 —	5	— 15	ns
TX_CLK data clock rise time, (20% to 80%)	t_{MTXR}	1.0	—	4.0	ns
TX_CLK data clock fall time, (80% to 20%)	t_{MTXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

This figure shows the MII transmit AC timing diagram.

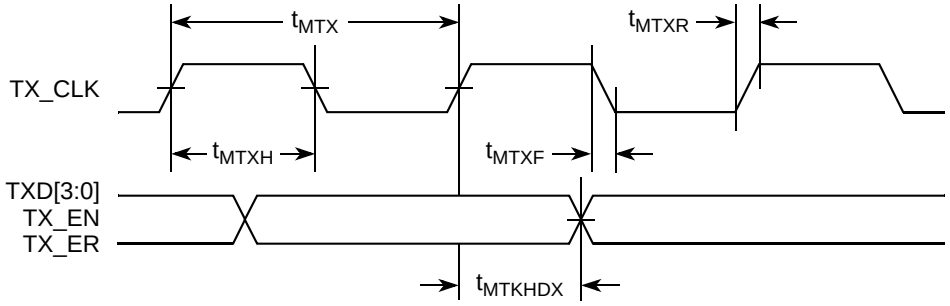


Figure 12. MII Transmit AC Timing Diagram

8.2.2.2 MII Receive AC Timing Specifications

This table provides the MII receive AC timing specifications.

Table 30. MII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise time, (20% to 80%)	t_{MRXR}	1.0	—	4.0	ns
RX_CLK clock fall time, (80% to 20%)	t_{MRXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

This figure provides the AC test load.

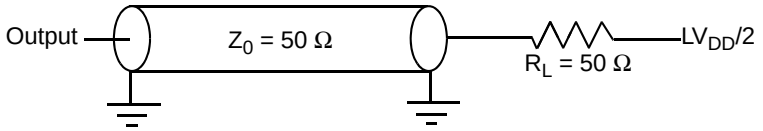


Figure 13. AC Test Load

This figure shows the MII receive AC timing diagram.

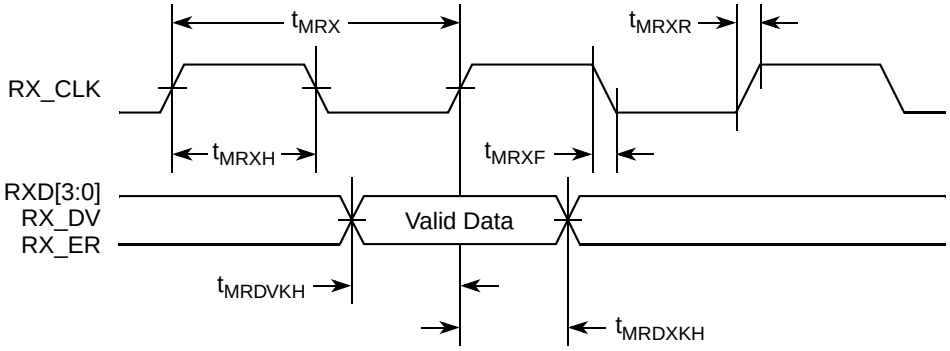


Figure 14. MII Receive AC Timing Diagram

Table 40. Local Bus General Timing Parameters—DLL Enabled (continued)

Parameter	Symbol[1]	Min	Max	Unit	Notes
LUPWAIT input hold from local bus clock	$t_{LBIXKH2}$	1.0	—	ns	3, 4
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT1}$	1.5	—	ns	5
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT2}$	3.0	—	ns	6
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT3}$	2.5	—	ns	7
Local bus clock to LALE rise	t_{LBKHLR}	—	4.5	ns	—
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	4.5	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	4.5	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	4.5	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	1.0	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	1.0	—	ns	3
Local bus clock to output high impedance for LAD/LDP	t_{LBKHOZ}	—	3.8	ns	8

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to rising edge of LSYNC_IN.
3. All signals are measured from $OV_{DD}/2$ of the rising edge of LSYNC_IN to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. $t_{LBOTOT1}$ should be used when RCWH[LALE] is not set and when the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
6. $t_{LBOTOT2}$ should be used when RCWH[LALE] is set and when the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
7. $t_{LBOTOT3}$ should be used when RCWH[LALE] is set and when the load on LALE output pin equals to the load on LAD output pins.
8. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

This table describes the general timing parameters of the local bus interface of the device.

Table 41. Local Bus General Timing Parameters—DLL Bypass Mode[9]

Parameter	Symbol[1]	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	15	—	ns	2
Input setup to local bus clock	t_{LBIVKH}	7	—	ns	3, 4
Input hold from local bus clock	t_{LBIXKH}	1.0	—	ns	3, 4
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT1}$	1.5	—	ns	5
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT2}$	3	—	ns	6
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT3}$	2.5	—	ns	7

These figures show the local bus signals.

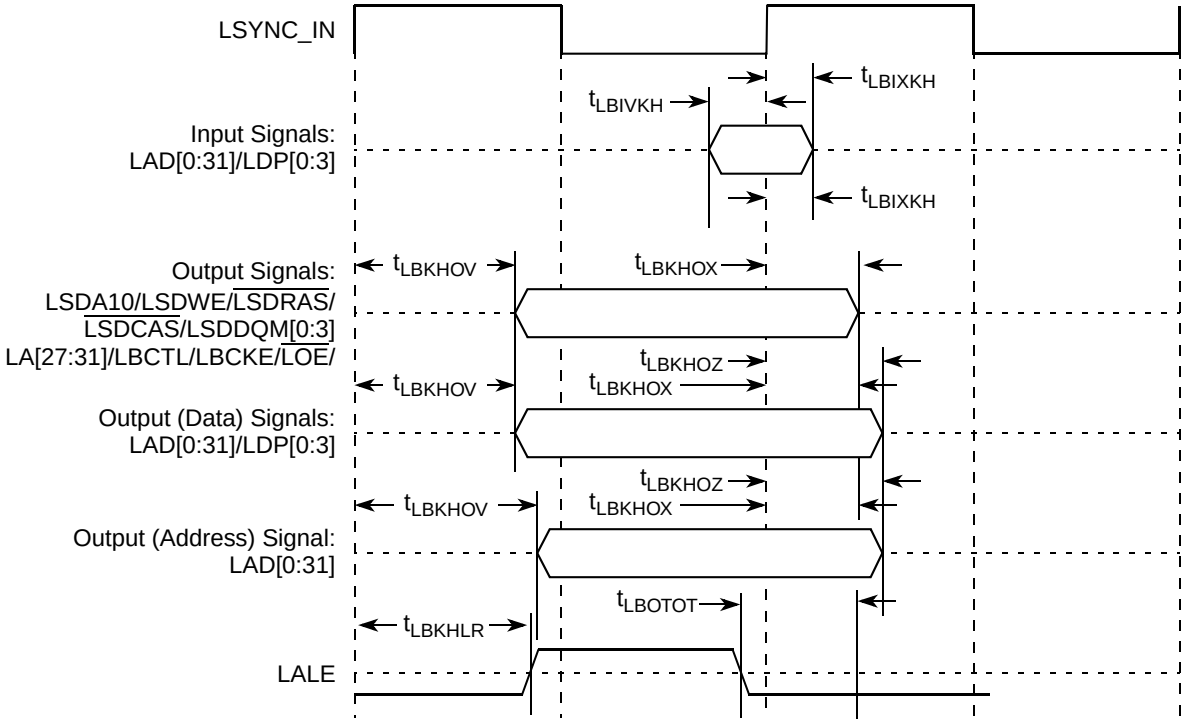


Figure 23. Local Bus Signals, Nonspecial Signals Only (DLL Enabled)

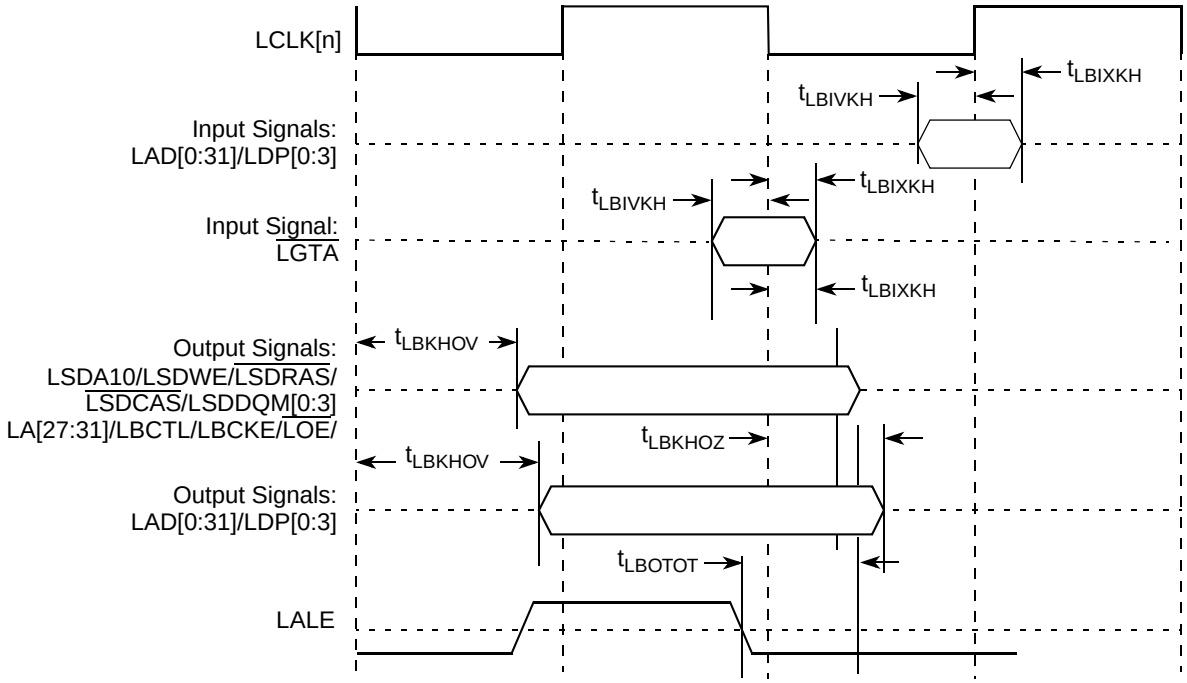


Figure 24. Local Bus Signals, Nonspecial Signals Only (DLL Bypass Mode)

This figure provides the AC test load for TDO and the boundary-scan outputs of the device.

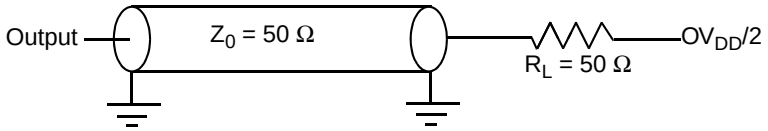


Figure 29. AC Test Load for the JTAG Interface

This figure provides the JTAG clock input timing diagram.

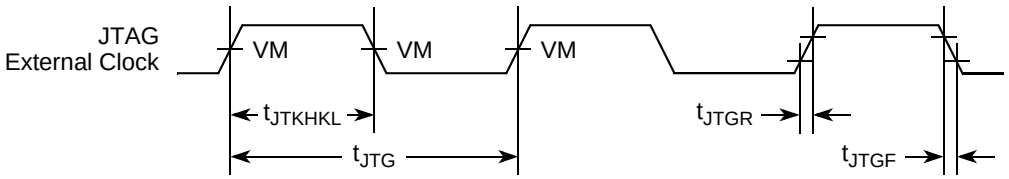


Figure 30. JTAG Clock Input Timing Diagram

This figure provides the $\overline{\text{TRST}}$ timing diagram.

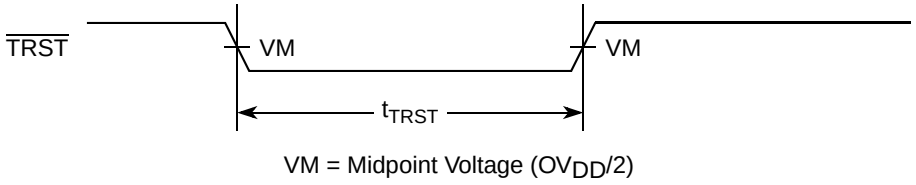


Figure 31. $\overline{\text{TRST}}$ Timing Diagram

This figure provides the boundary-scan timing diagram.

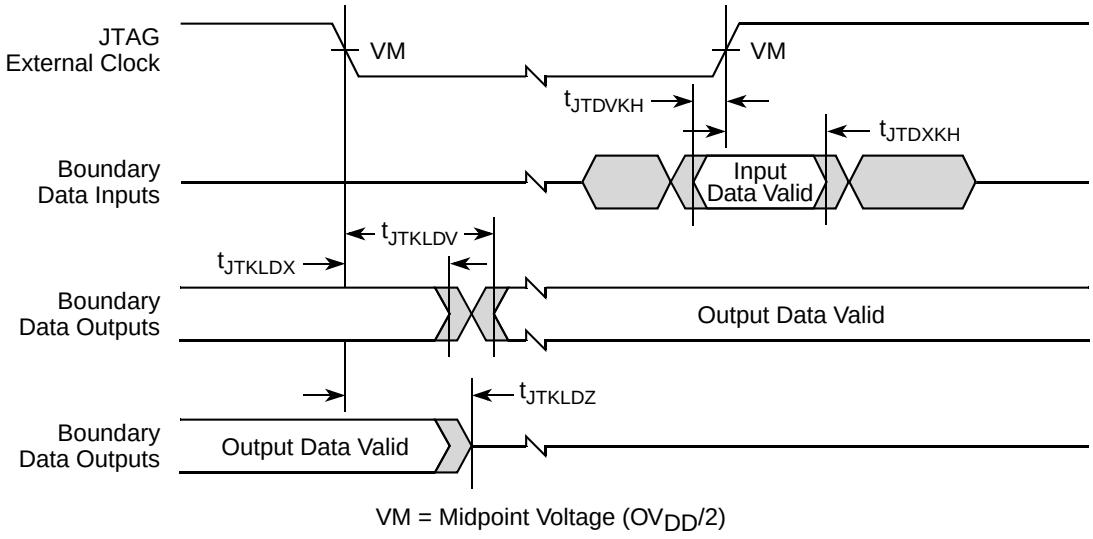


Figure 32. Boundary-Scan Timing Diagram

11.2 I²C AC Electrical Specifications

This table provides the AC timing parameters for the I²C interface of the device.

Table 45. I²C AC Electrical Specifications

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 44).

Parameter	Symbol[1]	Min	Max	Unit	Note
SCL clock frequency	f_{I2C}	0	400	kHz	2
Low period of the SCL clock	t_{I2CL}	1.3	—	μs	—
High period of the SCL clock	t_{I2CH}	0.6	—	μs	—
Setup time for a repeated START condition	t_{I2SVKH}	0.6	—	μs	—
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t_{I2SXKL}	0.6	—	μs	—
Data setup time	t_{I2DVKH}	100	—	ns	3
Data hold time: CBUS compatible masters I²C bus devices	t_{I2DXKL}	 — 0[2]	 — 0.9[3]	μs	—
Rise time of both SDA and SCL signals	t_{I2CR}	20 + 0.1 C_b[4]	300	ns	—
Fall time of both SDA and SCL signals	t_{I2CF}	20 + 0.1 C_b[4]	300	ns	—
Set-up time for STOP condition	t_{I2PVKH}	0.6	—	μs	—
Bus free time between a STOP and START condition	t_{I2KHDX}	1.3	—	μs	—
Noise margin at the LOW level for each connected device (including hysteresis)	V_{NL}	0.1 × OV_{DD}	—	V	—
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	0.2 × OV_{DD}	—	V	—

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the start condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the stop condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. The device provides a hold time of at least 300 ns for the SDA signal (referred to the V_{IH} min of the SCL signal) to bridge the undefined region of the falling edge of SCL.
3. The maximum t_{I2DVKH} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
4. C_B = capacitance of one bus line in pF.

Table 47. PCI AC Timing Specifications at 66 MHz (continued)

Parameter	Symbol[1]	Min	Max	Unit	Notes
Clock to output high impedance	t_{PCKHOZ}	—	14	ns	2, 3
Input setup to clock	t_{PCIVKH}	3.0	—	ns	2, 4
Input hold from clock	t_{PCIXKH}	0.3	—	ns	2, 4, 6

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the PCI_SYNC_IN clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
2. See the timing measurement conditions in the *PCI 2.2 Local Bus Specifications*.
3. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
4. Input timings are measured at the pin.
5. In rev. 2.0 silicon, due to errata, t_{PCIHOV} maximum is 6.6 ns. Refer to Errata PCI21 in *Chip Errata for the MPC8360E, Rev. 1*.
6. In rev. 2.0 silicon, due to errata, t_{PCIXKH} minimum is 1 ns. Refer to Errata PCI17 in *Chip Errata for the MPC8360E, Rev. 1*.

Table 48. PCI AC Timing Specifications at 33 MHz

Parameter	Symbol[1]	Min	Max	Unit	Notes
Clock to output valid	t_{PCKHOV}	—	11	ns	2
Output hold from clock	t_{PCKHOX}	2	—	ns	2
Clock to output high impedance	t_{PCKHOZ}	—	14	ns	2, 3
Input setup to clock	t_{PCIVKH}	7.0	—	ns	2, 2
Input hold from clock	t_{PCIXKH}	0.3	—	ns	2, 4, 5

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the PCI_SYNC_IN clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
2. See the timing measurement conditions in the *PCI 2.2 Local Bus Specifications*.
3. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
4. Input timings are measured at the pin.
5. In rev. 2.0 silicon, due to errata, t_{PCIXKH} minimum is 1 ns. Refer to Errata PCI17 in *Chip Errata for the MPC8360E, Rev. 1*.

This figure provides the AC test load for PCI.

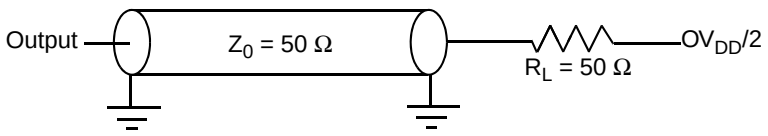
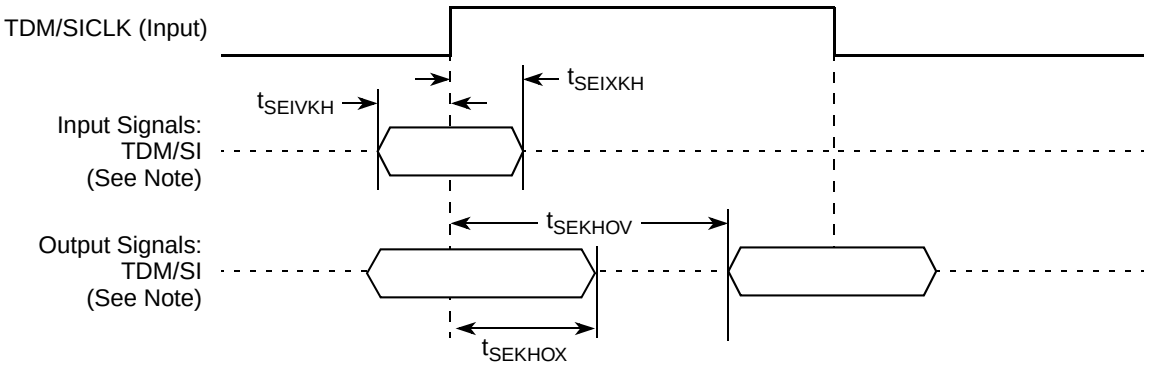


Figure 36. PCI AC Test Load

This figure shows the TDM/SI timing with external clock.



Note: The clock edge is selectable on TDM/SI

Figure 45. TDM/SI AC Timing (External Clock) Diagram

17.3 UTOPIA/POS

This section describes the DC and AC electrical specifications for the UTOPIA/POS of the MPC8360E/58E.

17.4 UTOPIA/POS DC Electrical Characteristics

This table provides the DC electrical characteristics for the device UTOPIA.

Table 59. UTOPIA DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –8.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 8.0 mA	—	0.5	V
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	0 V ≤V_{IN} ≤OV_{DD}	—	±10	μA

17.5 UTOPIA/POS AC Timing Specifications

This table provides the UTOPIA input and output AC timing specifications.

Table 60. UTOPIA AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Max	Unit	Notes
UTOPIA outputs—Internal clock delay	t_{UIKHOV}	0	11.5	ns	—
UTOPIA outputs—External clock delay	t_{UEKHOV}	1	11.6	ns	—
UTOPIA outputs—Internal clock high impedance	t_{UIKHOX}	0	8.0	ns	—
UTOPIA outputs—External clock high impedance	t_{UEKHOX}	1	10.0	ns	—
UTOPIA inputs—Internal clock input setup time	t_{UIIVKH}	6	—	ns	—
UTOPIA inputs—External clock input setup time	t_{UEIVKH}	4	—	ns	3

This figure shows the UTOPIA timing with internal clock.

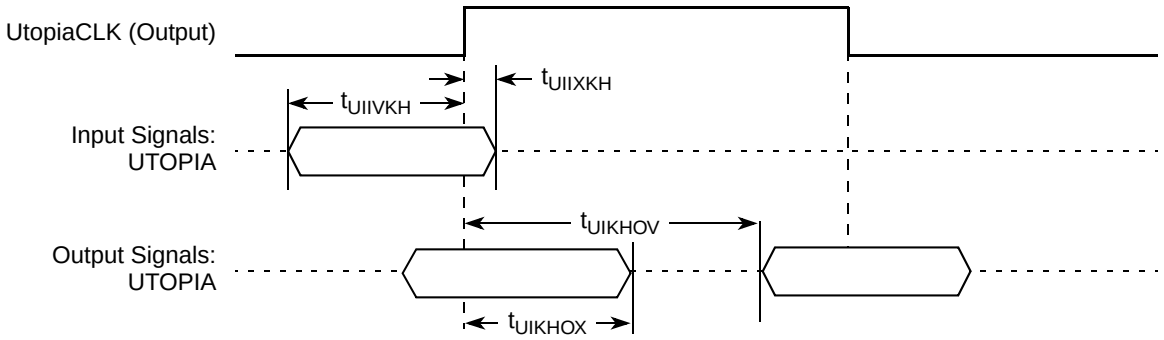


Figure 48. UTOPIA AC Timing (Internal Clock) Diagram

18 HDLC, BISYNC, Transparent, and Synchronous UART

This section describes the DC and AC electrical specifications for the high level data link control (HDLC), BISYNC, transparent, and synchronous UART protocols of the MPC8360E/58E.

18.1 HDLC, BISYNC, Transparent, and Synchronous UART DC Electrical Characteristics

This table provides the DC electrical characteristics for the device HDLC, BISYNC, transparent, and synchronous UART protocols.

Table 61. HDLC, BISYNC, Transparent, and Synchronous UART DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –2.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.5	V
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	0 V ≤V_{IN} ≤OV_{DD}	—	±10	μA

18.2 HDLC, BISYNC, Transparent, and Synchronous UART AC Timing Specifications

These tables provide the input and output AC timing specifications for HDLC, BISYNC, transparent, and synchronous UART protocols.

Table 62. HDLC, BISYNC, and Transparent AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Max	Unit
Outputs—Internal clock delay	t_{HIKHOV}	0	11.2	ns
Outputs—External clock delay	t_{HEKHOV}	1	10.8	ns

19 USB

This section provides the AC and DC electrical specifications for the USB interface of the MPC8360E/58E.

19.1 USB DC Electrical Characteristics

This table provides the DC electrical characteristics for the USB interface.

Table 64. USB DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2	OV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	–0.3	0.8	V
High-level output voltage, I_{OH} = –100 µA	V_{OH}	OV_{DD} – 0.4	—	V
Low-level output voltage, I_{OL} = 100 µA	V_{OL}	—	0.2	V
Input current	I_{IN}	—	±10	µA

19.2 USB AC Electrical Specifications

This table describes the general timing parameters of the USB interface of the device.

Table 65. USB General Timing Parameters

Parameter	Symbol[1]	Min	Max	Unit	Notes	Note
USB clock cycle time	t_{USCK}	20.83	—	ns	Full speed 48 MHz	—
USB clock cycle time	t_{USCK}	166.67	—	ns	Low speed 6 MHz	—
Skew between TXP and TXN	t_{USTSPN}	—	5	ns	—	2
Skew among RXP, RXN, and RXD	$t_{USRSPND}$	—	10	ns	Full speed transitions	2
Skew among RXP, RXN, and RXD	t_{USRPND}	—	100	ns	Low speed transitions	2

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(state)(signal)}}$ for receive signals and $t_{\text{(first two letters of functional block)(state)(signal)}}$ for transmit signals. For example, $t_{USRSPND}$ symbolizes USB timing (US) for the USB receive signals skew (RS) among RXP, RXN, and RXD (PND). Also, t_{USTSPN} symbolizes USB timing (US) for the USB transmit signals skew (TS) between TXP and TXN (PN).
2. Skew measurements are done at $OV_{DD}/2$ of the rising or falling edge of the signals.

This figure provide the AC test load for the USB.

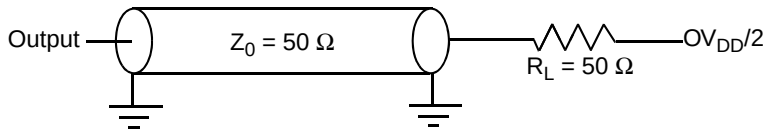


Figure 52. USB AC Test Load

Table 67. MPC8358E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{IRQ}}$[4:5]	G33, G32	I/O	OV_{DD}	—
$\overline{\text{IRQ}}$[6]/$\overline{\text{LCS}}$[6]/$\overline{\text{CKSTOP\_OUT}}$	E35	I/O	OV_{DD}	—
$\overline{\text{IRQ}}$[7]/$\overline{\text{LCS}}$[7]/$\overline{\text{CKSTOP\_IN}}$	H36	I/O	OV_{DD}	—
DUART				
UART1_SOUT/M1SRCID[0]/ M2SRCID[0]/LSRCID[0]	E32	O	OV_{DD}	—
UART1_SIN/M1SRCID[1]/ M2SRCID[1]/LSRCID[1]	B34	I/O	OV_{DD}	—
$\overline{\text{UART1\_CTS}}$/M1SRCID[2]/ M2SRCID[2]/LSRCID[2]	C34	I/O	OV_{DD}	—
$\overline{\text{UART1\_RTS}}$/M1SRCID[3]/ M2SRCID[3]/LSRCID[3]	A35	O	OV_{DD}	—
I^2C Interface				
IIC1_SDA	D34	I/O	OV_{DD}	2
IIC1_SCL	B35	I/O	OV_{DD}	2
IIC2_SDA	E33	I/O	OV_{DD}	2
IIC2_SCL	C35	I/O	OV_{DD}	2
QUICC Engine				
CE_PA[0]	F8	I/O	LV_{DD0}	—
CE_PA[1:2]	AH1, AG5	I/O	OV_{DD}	—
CE_PA[3:7]	F6, D4, C3, E5, A3	I/O	$LV_{DD}0$	—
CE_PA[8]	AG3	I/O	OV_{DD}	—
CE_PA[9:12]	F7, B3, E6, B4	I/O	$LV_{DD}0$	—
CE_PA[13:14]	AG1, AF6	I/O	OV_{DD}	—
CE_PA[15]	B2	I/O	$LV_{DD}0$	—
CE_PA[16]	AF4	I/O	OV_{DD}	—
CE_PA[17:21]	B16, A16, E17, A17, B17	I/O	$LV_{DD}1$	—
CE_PA[22]	AF3	I/O	OV_{DD}	—
CE_PA[23:26]	C18, D18, E18, A18	I/O	$LV_{DD}1$	—
CE_PA[27:28]	AF2, AE6	I/O	OV_{DD}	—
CE_PA[29]	B19	I/O	$LV_{DD}1$	—
CE_PA[30]	AE5	I/O	OV_{DD}	—
CE_PA[31]	F16	I/O	$LV_{DD}1$	—

Table 67. MPC8358E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$LV_{DD}1$	C17, D16	Power for UCC2 Ethernet interface option 1 (2.5 V, 3.3 V)	$LV_{DD}1$	9
$LV_{DD}2$	B18, E21	Power for UCC2 Ethernet interface option 2 (2.5 V, 3.3 V)	$LV_{DD}2$	9
V_{DD}	C36, D29, D35, E16, F9, F12, F15, F17, F18, F20, F21, F23, F25, F26, F29, F31, F32, F33, G6, J6, K32, M32, N6, P33, R6, R32, U32, V6, Y5, Y32, AB6, AB33, AD6, AF32, AK6, AL6, AM7, AM9, AM10, AM11, AM12, AM13, AM14, AM15, AM18, AM21, AM25, AM28, AM32, AN15, AN21, AN26, AU9, AU17	Power for core (1.2 V)	V_{DD}	—
OV_{DD}	A10, B9, B15, B32, C1, C12, C22, C29, D24, E3, E10, E27, G4, H35, J1, J35, K2, M4, N3, N34, R2, R37, T36, U2, U33, V4, V34, W3, Y35, Y37, AA1, AA36, AB2, AB34	PCI, 10/100 Ethernet, and other standard (3.3 V)	OV_{DD}	—
MVREF1	AN20	I	DDR reference voltage	—
MVREF2	AU32	I	DDR reference voltage	—
SPARE1	B11	I/O	OV_{DD}	8
SPARE3	AH32	—	GV_{DD}	8
SPARE4	AU18	—	GV_{DD}	7
SPARE5	AP1	—	GV_{DD}	8

Table 67. MPC8358E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
No Connect				
NC	AM16, AM17, AM20, AN13, AN16, AN17, AP10, AP11, AP13, AP15, AP18, AR11, AR13, AR14, AR15, AR16, AR17, AR20, AT11, AT12, AT13, AT14, AT16, AT17, AT18, AU10, AU11, AU12, AU13, AU15, AU19	—	—	—

Notes:

1. This pin is an open drain signal. A weak pull-up resistor (1 kΩ) should be placed on this pin to OV_{DD}.
2. This pin is an open drain signal. A weak pull-up resistor (2–10 kΩ) should be placed on this pin to OV_{DD}.
3. This output is actively driven during reset rather than being three-stated during reset.
4. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
5. This pin should have a weak pull up if the chip is in PCI host mode. Follow PCI specifications recommendation.
6. These are On Die Termination pins, used to control DDR2 memories internal termination resistance.
7. This pin must always be tied to GND.
8. This pin must always be left not connected.
9. Refer to *MPC8360E PowerQUICC II Pro Integrated Communications Processor Reference Manual* section on “RGMII Pins,” for information about the two UCC2 Ethernet interface options.
10. This pin must always be tied to GV_{DD}.
11. It is recommended that MDIC0 be tied to GND using an 18.2 Ω resistor and MDIC1 be tied to DDR power using an 18.2 Ω resistor for DDR2.

ordered, see Section 24.1, "Part Numbers Fully Addressed by this Document," for part ordering details and contact your Freescale sales representative or authorized distributor for more information.

Table 69. Operating Frequencies for the TBGA Package

Characteristic[1]	400 MHz	533 MHz	667 MHz[2]	Unit
e300 core frequency (*core_clk*)	266–400	266–533	266–667	MHz
Coherent system bus frequency (*csb_clk*)	133–333			MHz
QUICC Engine frequency[3] (*ce_clk*)	266–500			MHz
DDR and DDR2 memory bus frequency (MCLK)[4]	100–166.67			MHz
Local bus frequency (LCLK*n*)[5]	16.67–133			MHz
PCI input frequency (CLKIN or PCI_CLK)	25–66.67			MHz
Security core maximum internal operating frequency	133	133	166	MHz

Notes:
1. The CLKIN frequency, RCWL[SPMF], and RCWL[COREPLL] settings must be chosen such that the resulting *csb_clk*, MCLK, LCLK[0:2], and *core_clk* frequencies do not exceed their respective maximum or minimum operating frequencies.
2. The 667 MHz core frequency is based on a 1.3 V V_{DD} supply voltage.
3. The 500 MHz QE frequency is based on a 1.3 V V_{DD} supply voltage.
4. The DDR data rate is 2x the DDR memory bus frequency.
5. The local bus frequency is 1/2, 1/4, or 1/8 of the *lb_clk* frequency (depending on LCRR[CLKDIV]) which is in turn 1× or 2× the *csb_clk* frequency (depending on RCWL[LBCM]).

21.1 System PLL Configuration

The system PLL is controlled by the RCWL[SPMF] and RCWL[SVCOD] parameters. This table shows the multiplication factor encodings for the system PLL.

Table 70. System PLL Multiplication Factors

RCWL[SPMF]	System PLL Multiplication Factor
0000	× 16
0001	Reserved
0010	× 2
0011	× 3
0100	× 4
0101	× 5
0110	× 6
0111	× 7
1000	× 8
1001	× 9
1010	× 10
1011	× 11

Example 1. Sample Table Use

Index	SPMF	CORE PLL	CEPMF	CEPDF	Input Clock (MHz)	CSB Freq (MHz)	Core Freq (MHz)	QUICC Engine Freq (MHz)	400 (MHz)	533 (MHz)	667 (MHz)
A	**1000**	**0000011**	**01001**	**0**	33	266	400	300	∞	∞	∞
B	**0100**	**0000100**	**00110**	**0**	66	266	533	400	∞	∞	∞

- **Example A.** To configure the device with CSB clock rate of 266 MHz, core rate of 400 MHz, and QUICC Engine clock rate 300 MHz while the input clock rate is 33 MHz. Conf No. ‘s10’ and ‘c1’ are selected from Table 76. SPMF is 1000, CORPLL is 0000011, CEPMF is 01001, and CEPDF is 0.
- **Example B.** To configure the device with CSBCSB clock rate of 266 MHz, core rate of 533 MHz and QUICC Engine clock rate 400 MHz while the input clock rate is 66 MHz. Conf No. ‘s5h’ and ‘c2h’ are selected from Table 76. SPMF is 0100, CORPLL is 0000100, CEPMF is 00110, and CEPDF is 0.

22 Thermal

This section describes the thermal specifications of the MPC8360E/58E.

22.1 Thermal Characteristics

This table provides the package thermal characteristics for the 37.5 mm × 37.5 mm 740-TBGA package.

Table 77. Package Thermal Characteristics for the TBGA Package

Characteristic	Symbol	Value	Unit	Notes
Junction-to-ambient natural convection on single-layer board (1s)	$R_{\theta JA}$	15	°C/W	1, 2
Junction-to-ambient natural convection on four-layer board (2s2p)	$R_{\theta JA}$	11	°C/W	1, 3
Junction-to-ambient (@1 m/s) on single-layer board (1s)	$R_{\theta JMA}$	10	°C/W	1, 3
Junction-to-ambient (@ 1 m/s) on four-layer board (2s2p)	$R_{\theta JMA}$	8	°C/W	1, 3
Junction-to-ambient (@ 2 m/s) on single-layer board (1s)	$R_{\theta JMA}$	9	°C/W	1, 3
Junction-to-ambient (@ 2 m/s) on four-layer board (2s2p)	$R_{\theta JMA}$	7	°C/W	1, 3
Junction-to-board thermal	$R_{\theta JB}$	4.5	°C/W	4
Junction-to-case thermal	$R_{\theta JC}$	1.1	°C/W	5